



Automatic RF Techniques Group

58th Microwave Measurements Conference

RF Measurements for a Wireless World

Mission Valley Doubletree Hotel • San Diego, California

November 29th & 30th 2001

FINAL CALL FOR PAPERS

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Jim Taylor, Executive Secretary

Join us in exploring cutting edge measurements for the rapidly expanding field of RF telecommunications. We encourage submission of original papers demonstrating your approach to measurements of wireless and broadband communications on topics including:

- performance of deployed technologies such as GSM, CDMA, & 802.11
- performance of new technologies as Bluetooth, Home RF, WCDMA & CDMA 2000
- adjacent & co-channel interference and their effects on receiver sensitivity & BER
- modulated signal characteristics & in-band and out-of-band spurious performance
- relationships between baseband and rf systems performance and measurements
- time-domain measurement, characterization, and models of communication systems
- large-signal measurements related to telecommunications

Papers are also invited for our two special sessions:

- Nonlinear Microwave Measurement
- Accuracy in RF Measurement

as well as other areas of automated RF measurements

DEADLINES

September 10th Electronic Abstract/Summary due

October 15th Electronic full camera-ready paper in pdf format due

Paper acceptance and classification will be communicated by Sept. 21st, 2001. Information can be found in the Abstract/Summary Submission Instructions on our Web site, www.arftg.org

NIST/ARFTG MEASUREMENTS SHORT COURSE

Join us in a practical microwave measurement tutorial. Day 1: Microwave measurements overview; circuit theory; VNA; interconnects and IC test fixtures and probing, RF connectors; on-wafer measurements; power; thermal noise; phase noise; Day 2: Uncertainty analysis; digital modulation; time-domain network analysis; overview of wireless test instrumentation and measurement; introduction to nonlinear measurements. Fee: \$400 for 1-1/2 day course. Contact Dave Walker (dwalker@boulder.nist.gov) 303-497-5490 for more information.

NONLINEAR MEASUREMENTS WORKSHOP

Present your latest results at the ARFTG Nonlinear Measurements Workshop! The workshop will cover recent developments in load-pull measurements, nonlinear network analysis, and prediction of system parameters from nonlinear measurements. Contact Dave Walker (dwalker@boulder.nist.gov) or Paul Tasker (tasker@cf.ac.uk) about participation.

EXHIBITS

The 58th ARFTG Conference also offers an outstanding exhibition opportunity. Please contact our Exhibits Chair directly for further information (Leonard@cmicro.com).



www.arftg.org

